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Serial EEPROM Series Standard EEPROM

# I<sup>2</sup>C BUS EEPROM (2-Wire)

## BR24G128-3

### General Description

BR24G128-3 series is a serial EEPROM of I<sup>2</sup>C BUS Interface Method

### Features

- Completely conforming to the world standard I<sup>2</sup>C BUS.  
All controls available by 2 ports of serial clock (SCL) and serial data (SDA)
- Other devices than EEPROM can be connected to the same port, saving microcontroller port
- 1.6V to 5.5V Single Power Source Operation most suitable for battery use
- 1.6V to 5.5V wide limit of operating voltage, possible FAST MODE 400kHz operation
- Page Write Mode useful for initial value write at factory shipment
- Self-timed Programming Cycle
- Low Current Consumption
- Prevention of Write Mistake
  - Write (Write Protect) Function Added
  - Prevention of Write Mistake At Low Voltage
- More than 1 million write cycles
- More than 40 years data retention
- Noise filter built in SCL / SDA terminal
- Initial delivery state FFh

### Packages W(Typ) x D(Typ) x H(Max)

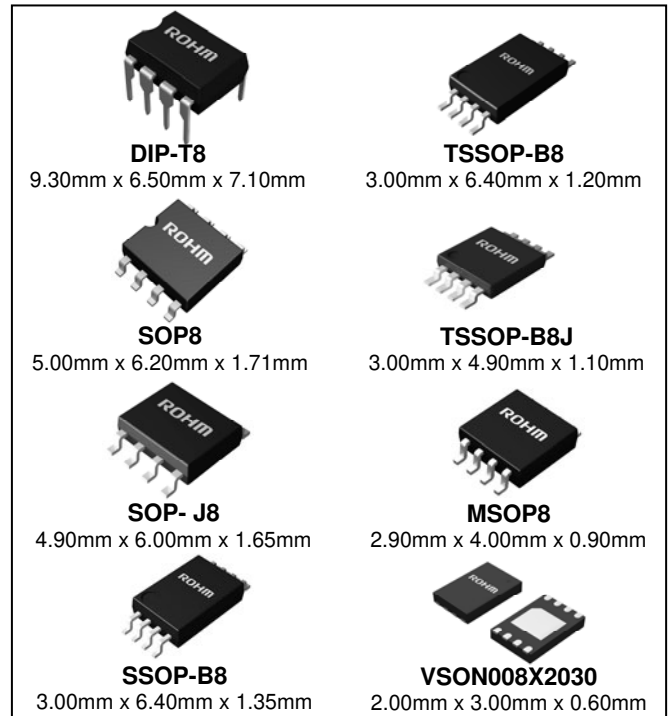


Figure 1.

### BR24G128-3

Capacity	Bit Format	Type	Power Source Voltage	Package
128Kbit	16Kx8	BR24G128-3	1.6V to 5.5V	DIP-T8
		BR24G128F-3		SOP8
		BR24G128FJ-3		SOP-J8
		BR24G128FV-3		SSOP-B8
		BR24G128FVT-3		TSSOP-B8
		BR24G128FVJ-3		TSSOP-B8J
		BR24G128FVM-3		MSOP8
		BR24G128NUX-3		VSON008X2030

○Product structure : Silicon monolithic integrated circuit ○This product has no designed protection against radioactive rays

**Absolute Maximum Ratings** (Ta=25°C)

Parameter	Symbol	Rating	Unit	Remark
Supply Voltage	V <sub>CC</sub>	-0.3 to +6.5	V	
Power Dissipation	Pd	450 (SOP8)	mW	Derate by 4.5mW/°C when operating above Ta=25°C
		450 (SOP-J8)		Derate by 4.5mW/°C when operating above Ta=25°C
		300 (SSOP-B8)		Derate by 3.0mW/°C when operating above Ta=25°C
		330 (TSSOP-B8)		Derate by 3.3mW/°C when operating above Ta=25°C
		310 (TSSOP-B8J)		Derate by 3.1mW/°C when operating above Ta=25°C
		310 (MSOP8)		Derate by 3.1mW/°C when operating above Ta=25°C
		300 (VSON008X2030)		Derate by 3.0mW/°C when operating above Ta=25°C
		800 (DIP-T8)		Derate by 8.0mW/°C when operating above Ta=25°C
Storage Temperature	T <sub>stg</sub>	-65 to +150	°C	
Operating Temperature	T <sub>opr</sub>	-40 to +85	°C	
Input Voltage / Output Voltage	-	-0.3 to V <sub>CC</sub> +1.0	V	The Max value of Input Voltage/Output Voltage is not over 6.5V. When the pulse width is 50ns or less, the Min value of Input Voltage/Output Voltage is not lower than -1.0V.
Junction Temperature	T <sub>jmax</sub>	150	°C	Junction temperature at the storage condition
Electrostatic discharge voltage (human body model)	V <sub>ESD</sub>	-4000 to +4000	V	

**Memory Cell Characteristics** (Ta=25°C, V<sub>CC</sub>=1.6V to 5.5V)

Parameter	Limit			Unit
	Min	Typ	Max	
Write Cycles <sup>(1)</sup>	1,000,000	-	-	Times
Data Retention <sup>(1)</sup>	40	-	-	Years

(1) Not 100% TESTED

**Recommended Operating Ratings**

Parameter	Symbol	Rating	Unit
Power Source Voltage	V <sub>CC</sub>	1.6 to 5.5	V
Input Voltage	V <sub>IN</sub>	0 to V <sub>CC</sub>	

**DC Characteristics** (Unless otherwise specified, Ta=-40°C to +85°C, V<sub>CC</sub>=1.6V to 5.5V)

Parameter	Symbol	Limit			Unit	Conditions
		Min	Typ	Max		
Input High Voltage1	V <sub>IH1</sub>	0.7V <sub>CC</sub>	-	V <sub>CC</sub> +1.0	V	1.7V ≤ V <sub>CC</sub> ≤ 5.5V
Input Low Voltage1	V <sub>IL1</sub>	-0.3 <sup>(2)</sup>	-	+0.3V <sub>CC</sub>	V	1.7V ≤ V <sub>CC</sub> ≤ 5.5V
Input High Voltage2	V <sub>IH2</sub>	0.8V <sub>CC</sub>	-	V <sub>CC</sub> +1.0	V	1.6V ≤ V <sub>CC</sub> < 1.7V
Input Low Voltage2	V <sub>IL2</sub>	-0.3 <sup>(2)</sup>	-	+0.2V <sub>CC</sub>	V	1.6V ≤ V <sub>CC</sub> < 1.7V
Output Low Voltage1	V <sub>OL1</sub>	-	-	0.4	V	I <sub>OL</sub> =3.0mA, 2.5V ≤ V <sub>CC</sub> ≤ 5.5V (SDA)
Output Low Voltage2	V <sub>OL2</sub>	-	-	0.2	V	I <sub>OL</sub> =0.7mA, 1.6V ≤ V <sub>CC</sub> < 2.5V (SDA)
Input Leakage Current	I <sub>LI</sub>	-1	-	+1	μA	V <sub>IN</sub> =0 to V <sub>CC</sub>
Output Leakage Current	I <sub>LO</sub>	-1	-	+1	μA	V <sub>OUT</sub> =0 to V <sub>CC</sub> (SDA)
Supply Current (Write)	I <sub>CC1</sub>	-	-	2.5	mA	V <sub>CC</sub> =5.5V, f <sub>SCL</sub> =400kHz, t <sub>WR</sub> =5ms, Byte write, Page write
Supply Current (Read)	I <sub>CC2</sub>	-	-	0.5	mA	V <sub>CC</sub> =5.5V, f <sub>SCL</sub> =400kHz Random read, current read, sequential read
Standby Current	I <sub>SB</sub>	-	-	2.0	μA	V <sub>CC</sub> =5.5V, SDA · SCL=V <sub>CC</sub> A0,A1,A2=GND, WP=GND

(2) When the pulse width is 50ns or less, it is -1.0V.

**AC Characteristics** (Unless otherwise specified, Ta=-40°C to +85°C, V<sub>CC</sub>=1.6V to 5.5V)

Parameter	Symbol	Limit			Unit
		Min	Typ	Max	
Clock Frequency	f <sub>SCL</sub>	-	-	400	kHz
Data Clock High Period	t <sub>HIGH</sub>	0.6	-	-	μs
Data Clock Low Period	t <sub>LOW</sub>	1.2	-	-	μs
SDA, SCL (INPUT) Rise Time <sup>(1)</sup>	t <sub>R</sub>	-	-	1.0	μs
SDA, SCL (INPUT) Fall Time <sup>(1)</sup>	t <sub>F1</sub>	-	-	1.0	μs
SDA (OUTPUT) Fall Time <sup>(1)</sup>	t <sub>F2</sub>	-	-	0.3	μs
Start Condition Hold Time	t <sub>HD:STA</sub>	0.6	-	-	μs
Start Condition Setup Time	t <sub>SU:STA</sub>	0.6	-	-	μs
Input Data Hold Time	t <sub>HD:DAT</sub>	0	-	-	ns
Input Data Setup Time	t <sub>SU:DAT</sub>	100	-	-	ns
Output Data Delay Time	t <sub>PD</sub>	0.1	-	0.9	μs
Output Data Hold Time	t <sub>DH</sub>	0.1	-	-	μs
Stop Condition Setup Time	t <sub>SU:STO</sub>	0.6	-	-	μs
Bus Free Time	t <sub>BUF</sub>	1.2	-	-	μs
Write Cycle Time	t <sub>WR</sub>	-	-	5	ms
Noise Spike Width (SDA and SCL)	t <sub>I</sub>	-	-	0.1	μs
WP Hold Time	t <sub>HD:WP</sub>	1.0	-	-	μs
WP Setup Time	t <sub>SU:WP</sub>	0.1	-	-	μs
WP High Period	t <sub>HIGH:WP</sub>	1.0	-	-	μs

(1) Not 100% TESTED.  
 Condition Input data level: V<sub>IL</sub>=0.2×V<sub>CC</sub> V<sub>IH</sub>=0.8×V<sub>CC</sub>  
 Input data timing reference level: 0.3×V<sub>CC</sub>/0.7×V<sub>CC</sub>  
 Output data timing reference level: 0.3×V<sub>CC</sub>/0.7×V<sub>CC</sub>  
 Rise/Fall time : ≤20ns

**Serial Input / Output Timing**

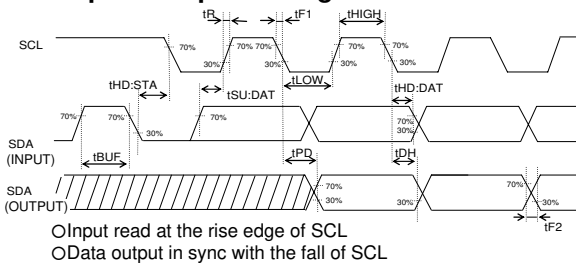


Figure 2-(a). Serial Input / Output Timing

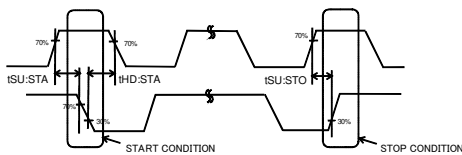


Figure 2-(b). Start-Stop Bit Timing

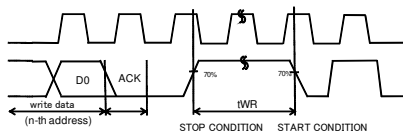


Figure 2-(c). Write Cycle Timing

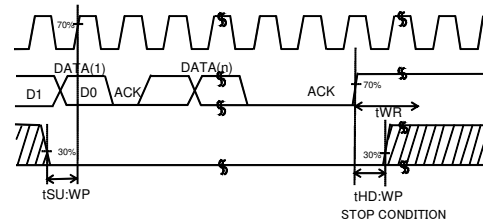


Figure 2-(d). WP Timing at Write Execution

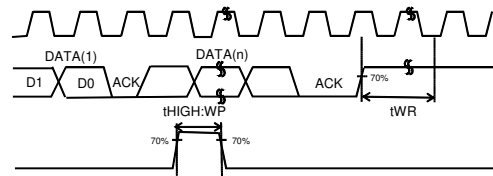


Figure 2-(e). WP Timing at Write Cancel

## Block Diagram

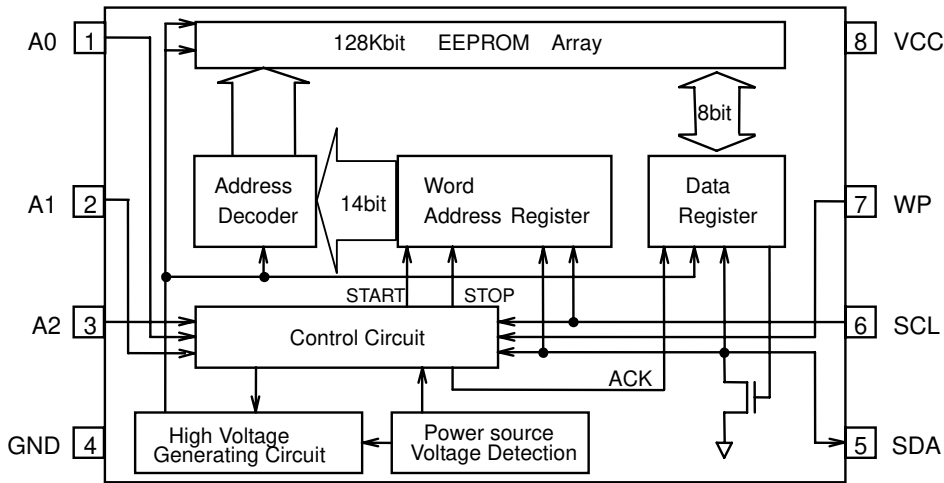
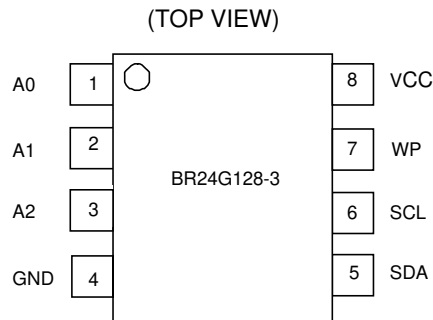


Figure 3. Block Diagram

## Pin Configuration



## Pin Descriptions

Terminal Name	Input/Output	Descriptions
A0	Input	Slave address setting*
A1	Input	Slave address setting*
A2	Input	Slave address setting*
GND	-	Reference voltage of all input / output, 0V
SDA	Input/Output	Serial data input serial data output
SCL	Input	Serial clock input
WP	Input	Write protect terminal
VCC	-	Connect the power source.

\*A0, A1 and A2 are not allowed to use as open.

Typical Performance Curves

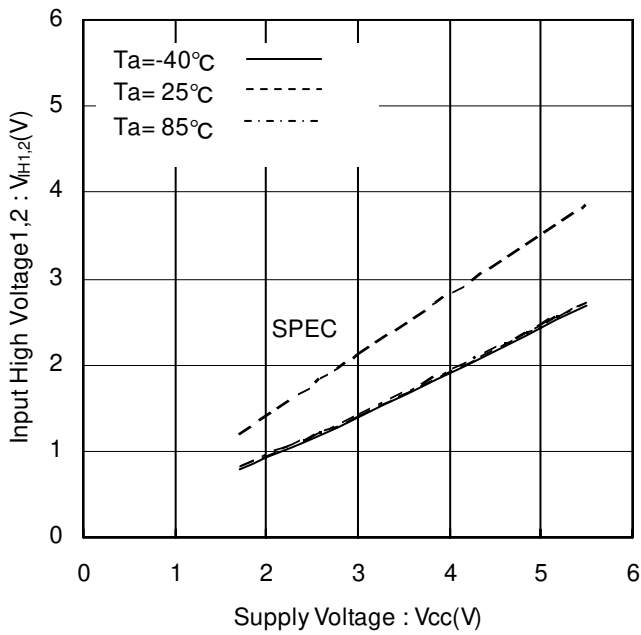


Figure 4. Input High Voltage1,2 vs Supply Voltage (A0, A1, A2, SCL, SDA, WP)

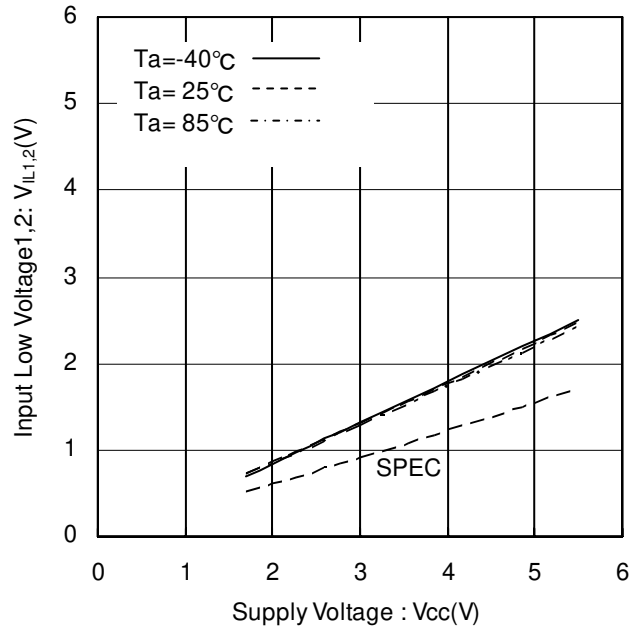


Figure 5. Input Low Voltage1,2 vs Supply Voltage (A0, A1, A2, SCL, SDA, WP)

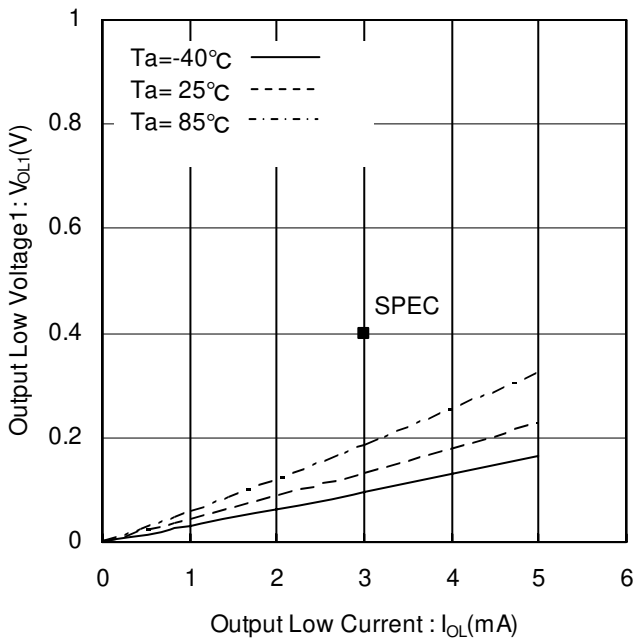


Figure 6. Output Low Voltage1 vs Output Low Current (V<sub>CC</sub>=2.5V)

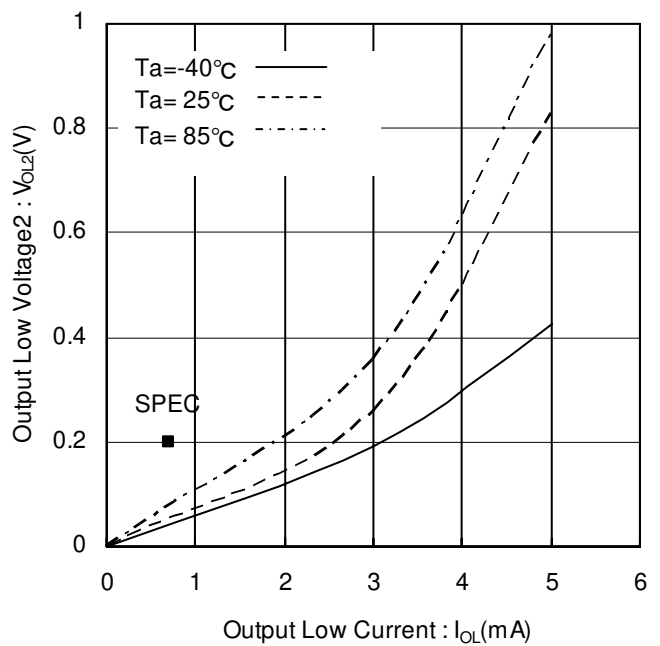


Figure 7. Output Low Voltage2 vs Output Low Current (V<sub>CC</sub>=1.6V)

Typical Performance Curves - continued

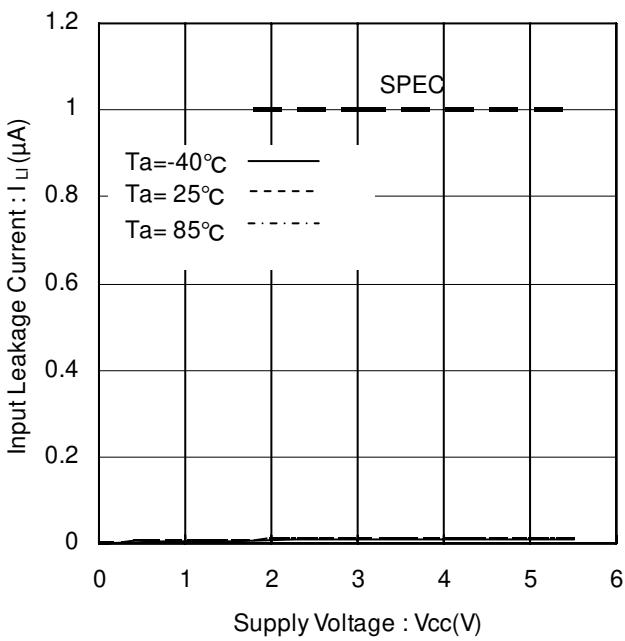


Figure 8. Input Leakage Current vs Supply Voltage (A0, A1, A2, SCL, WP)

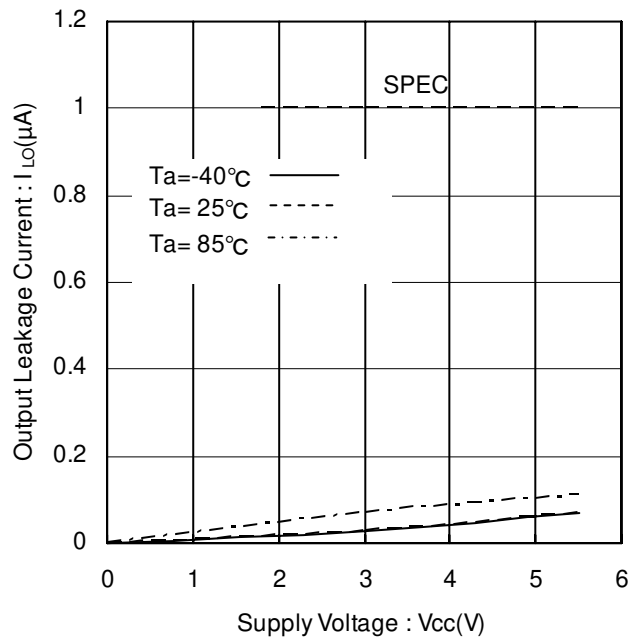


Figure 9. Output Leakage Current vs Supply Voltage (SDA)

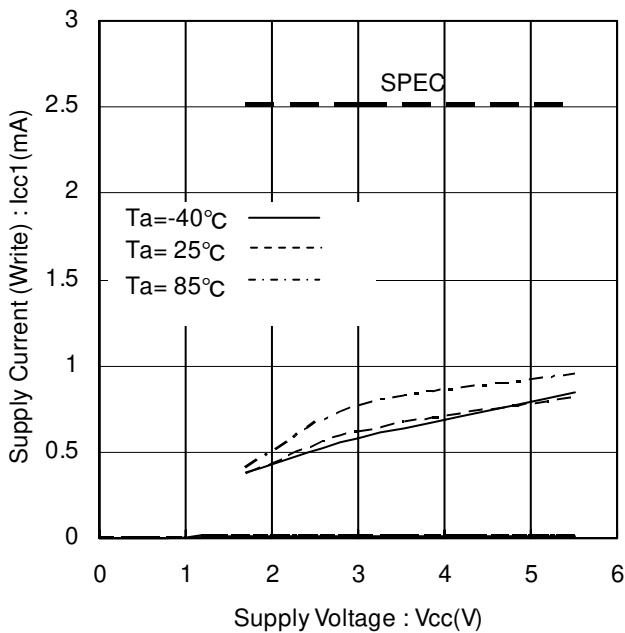


Figure 10. Supply Current (Write) vs Supply Voltage (f<sub>SCL</sub>=400kHz)

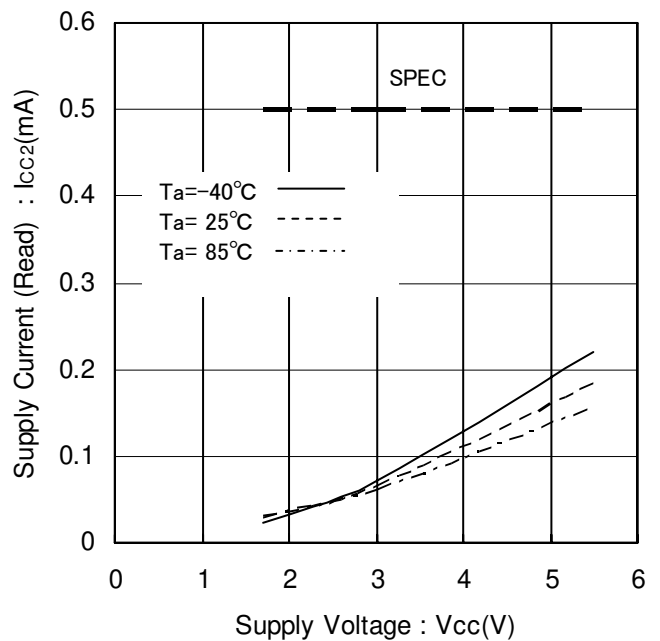


Figure 11. Supply Current (Read) vs Supply Voltage (f<sub>SCL</sub>=400kHz)

Typical Performance Curves - continued

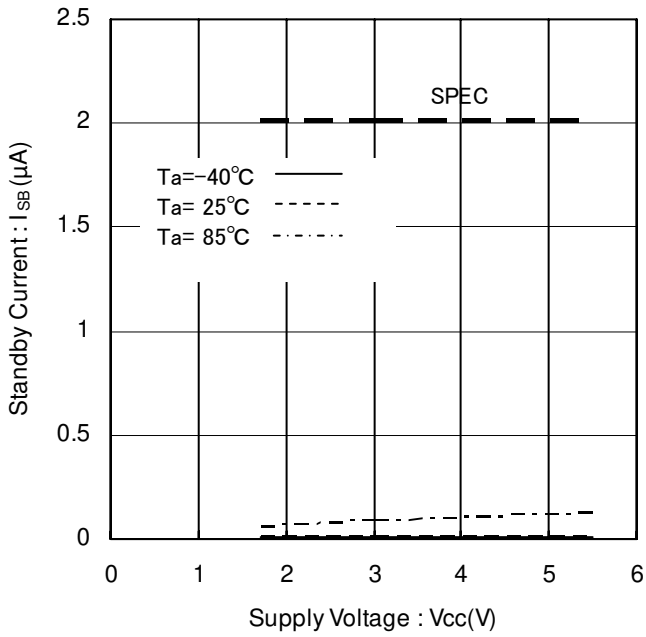


Figure 12. Standby Current vs Supply Voltage

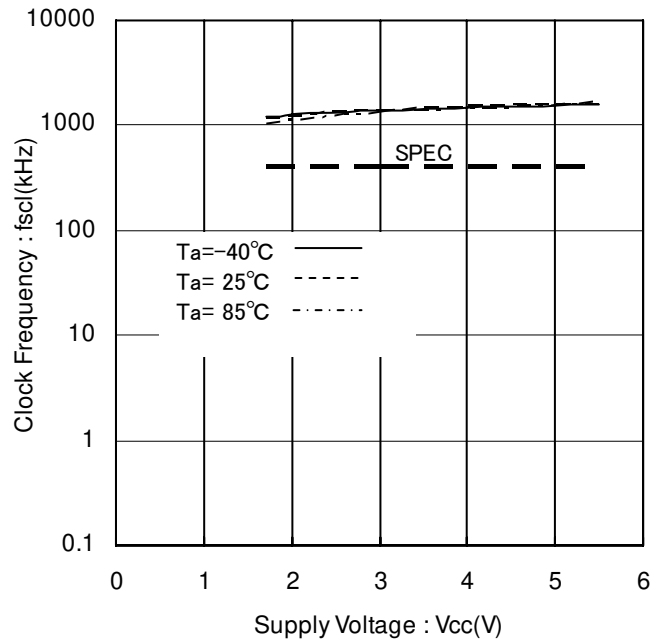


Figure 13. Clock Frequency vs Supply Voltage

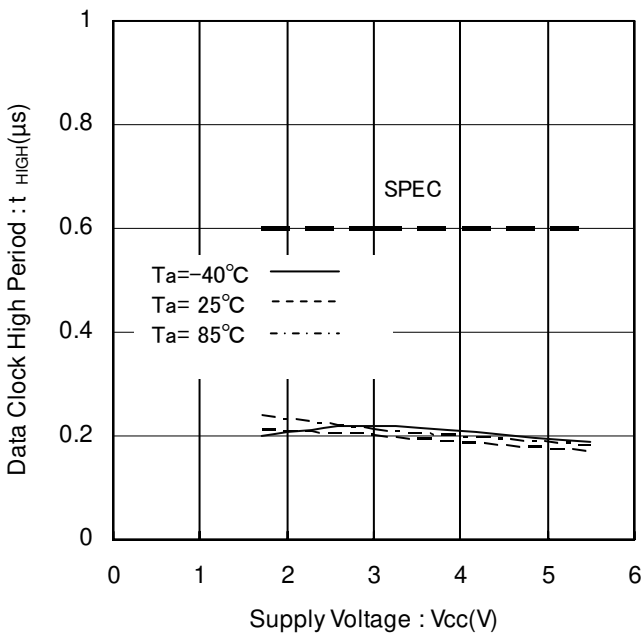


Figure 14. Data Clock High Period vs Supply Voltage

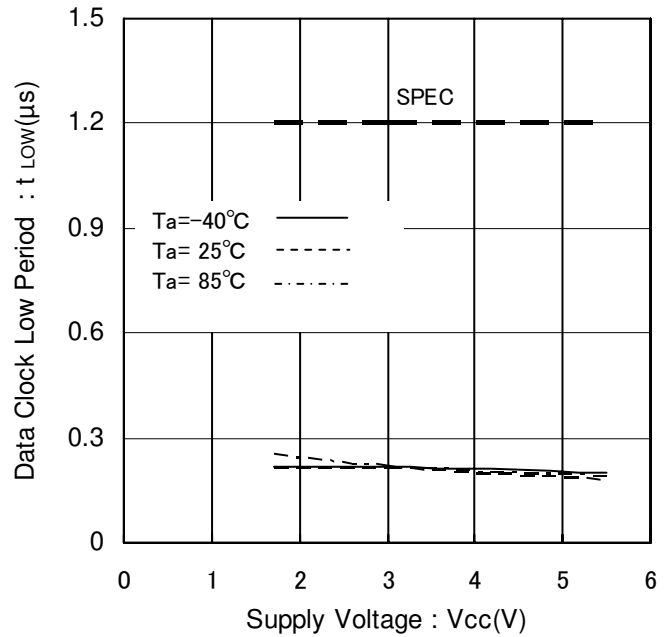


Figure 15. Data Clock Low Period vs Supply Voltage



Typical Performance Curves - continued

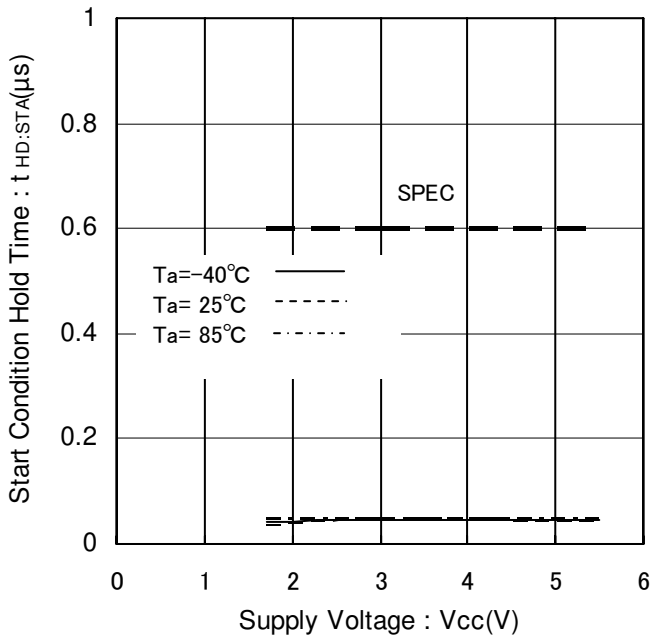


Figure 16. Start Condition Hold Time vs Supply Voltage

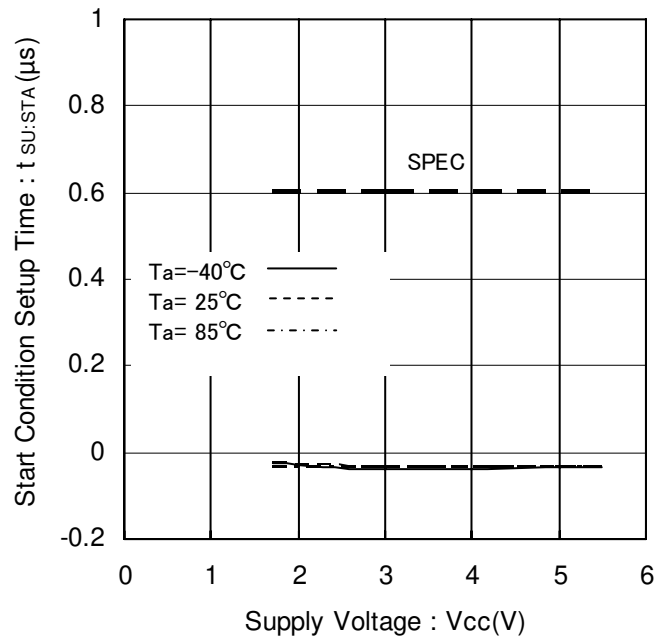


Figure 17. Start Condition Setup Time vs Supply Voltage

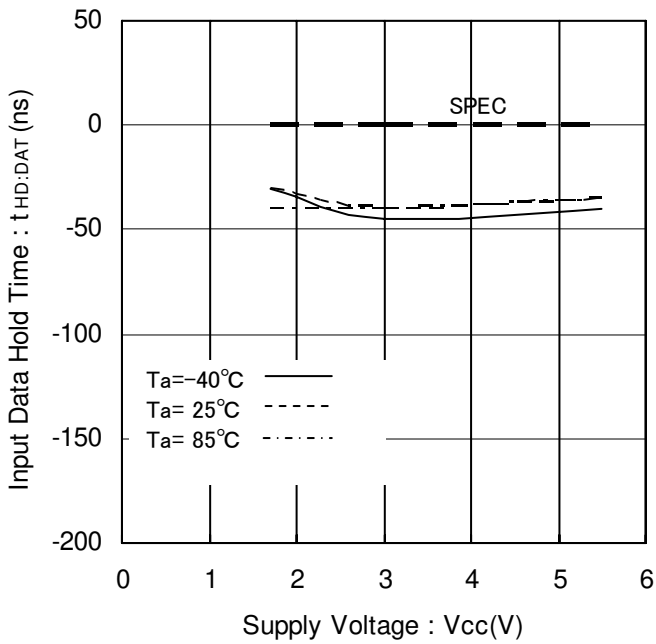


Figure 18. Input Data Hold Time vs Supply Voltage (HIGH)

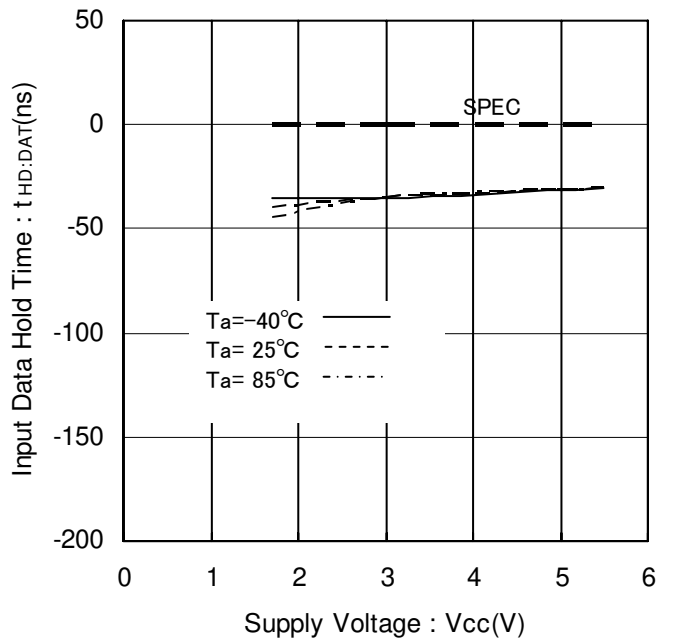


Figure 19. Input Data Hold Time vs Supply Voltage (LOW)

Typical Performance Curves - continued

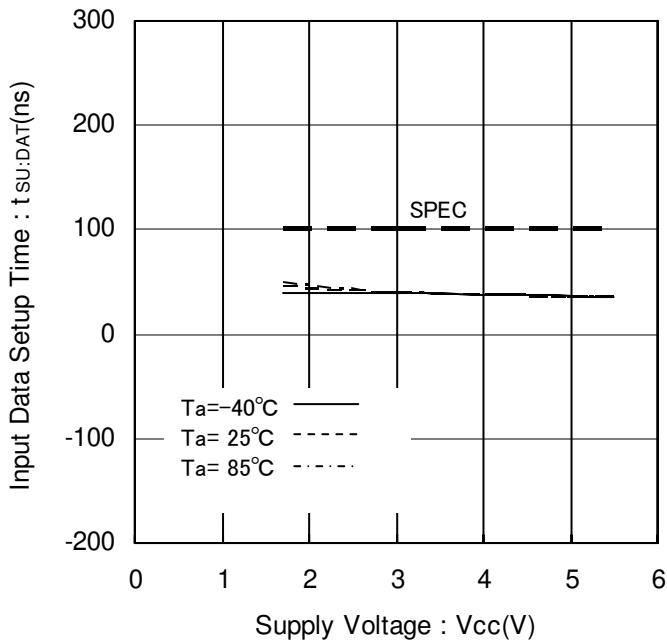


Figure 20. Input Data Setup Time vs Supply Voltage (HIGH)

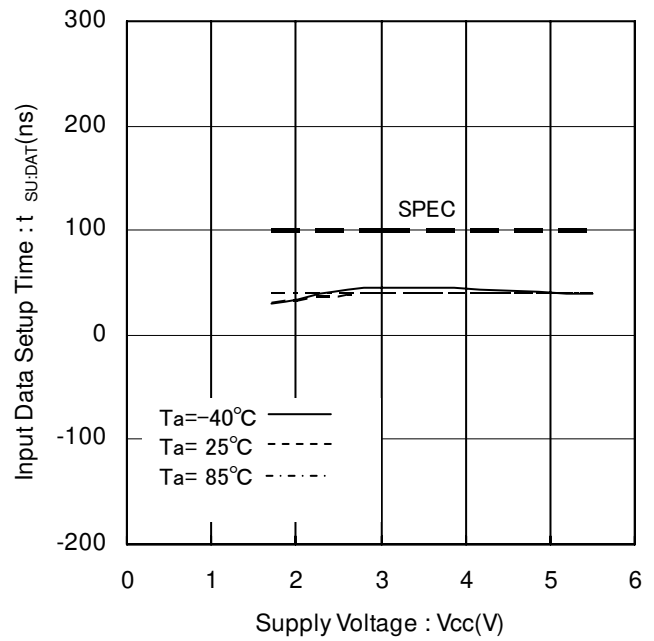


Figure 21. Input Data Setup Time vs Supply Voltage (LOW)

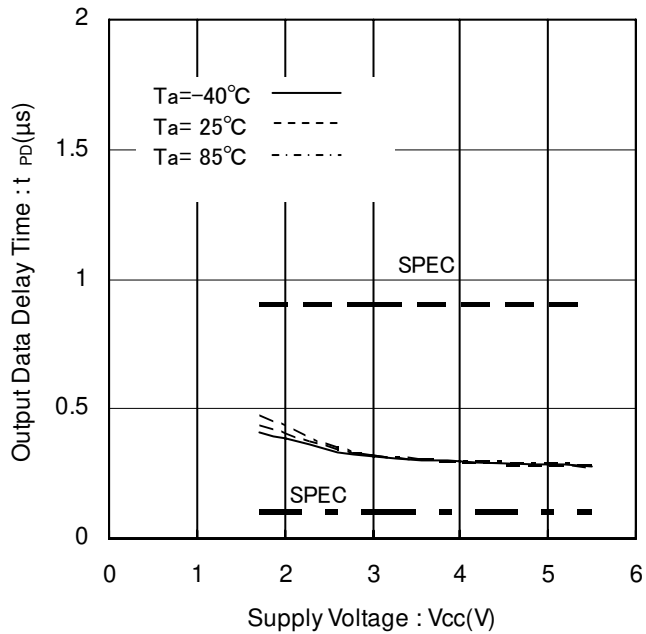


Figure 22. Output Data Delay Time vs Supply Voltage (LOW)

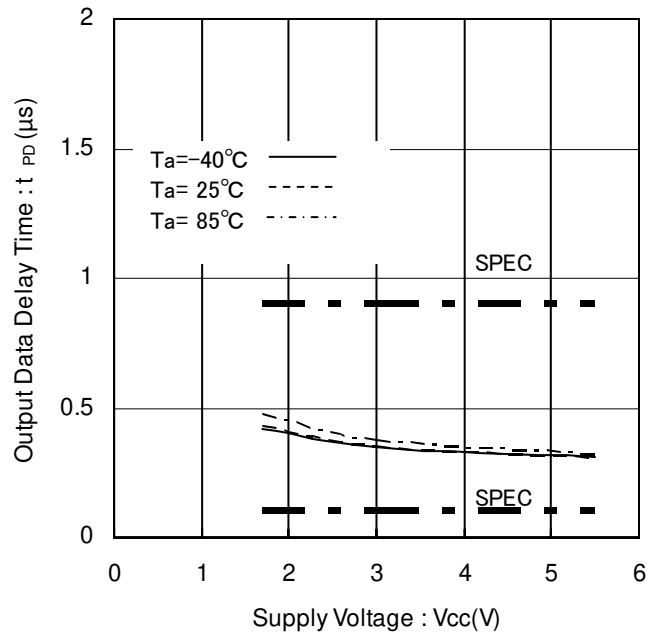


Figure 23. Output Data Delay Time vs Supply Voltage (HIGH)

Typical Performance Curves - continued

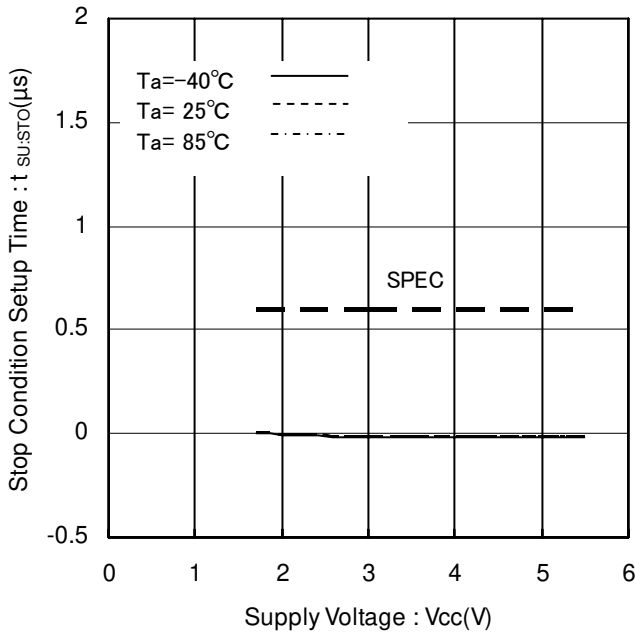


Figure 24. Stop Condition Setup Time vs Supply Voltage

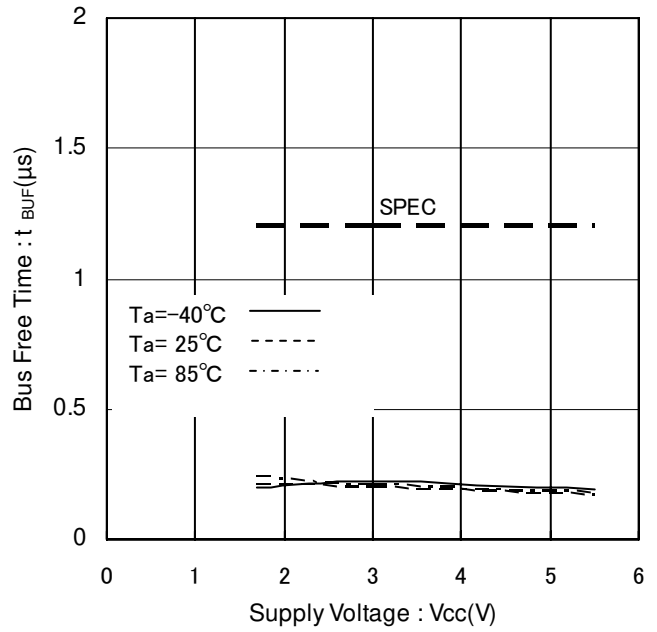


Figure 25. Bus Free Time vs Supply Voltage

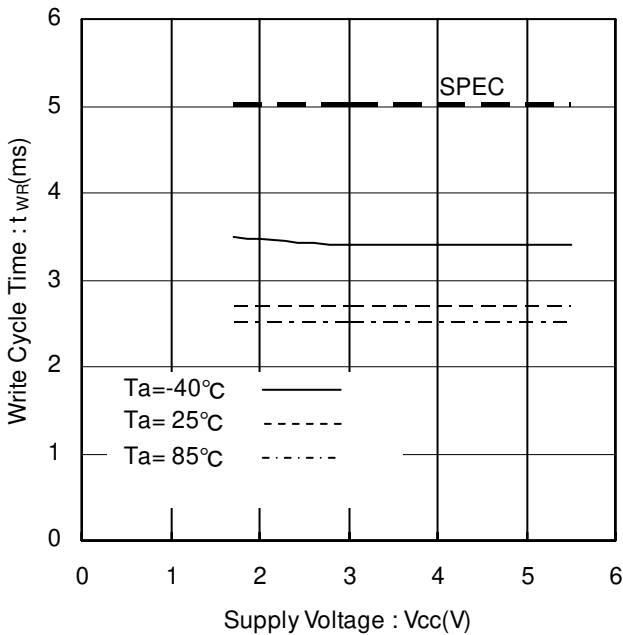


Figure 26. Write Cycle Time vs Supply Voltage

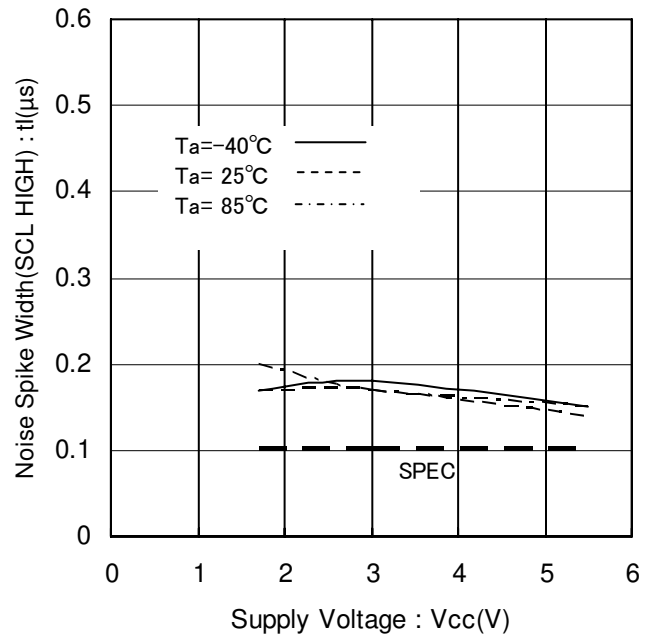


Figure 27. Noise Spike Width vs Supply Voltage (SCL HIGH)

Typical Performance Curves - continued

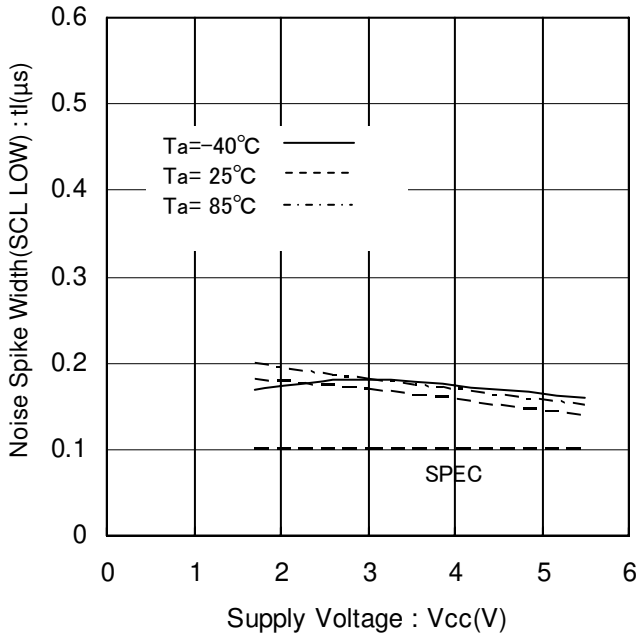


Figure 28. Noise Spike Width vs Supply Voltage (SCL LOW)

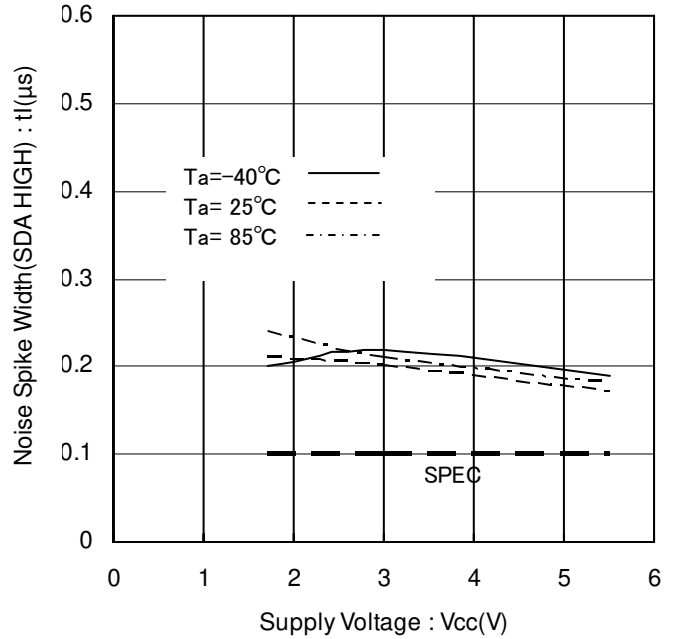


Figure 29. Noise Spike Width vs Supply Voltage (SDA HIGH)

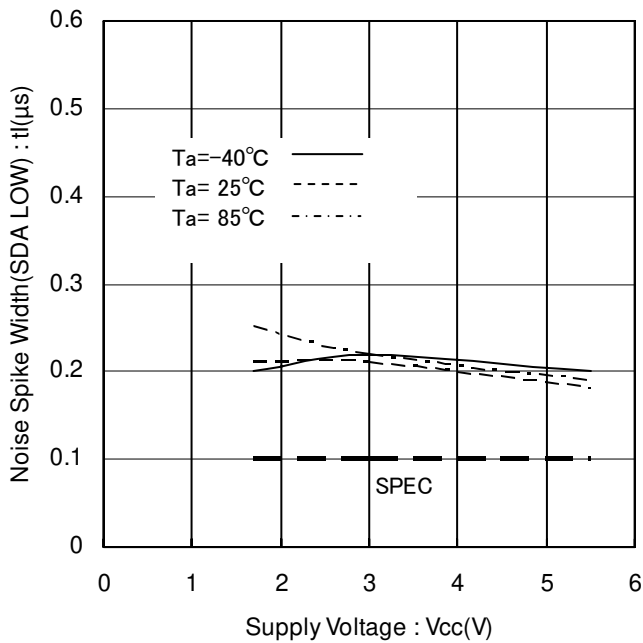


Figure 30. Noise Spike Width vs Supply Voltage (SDA LOW)

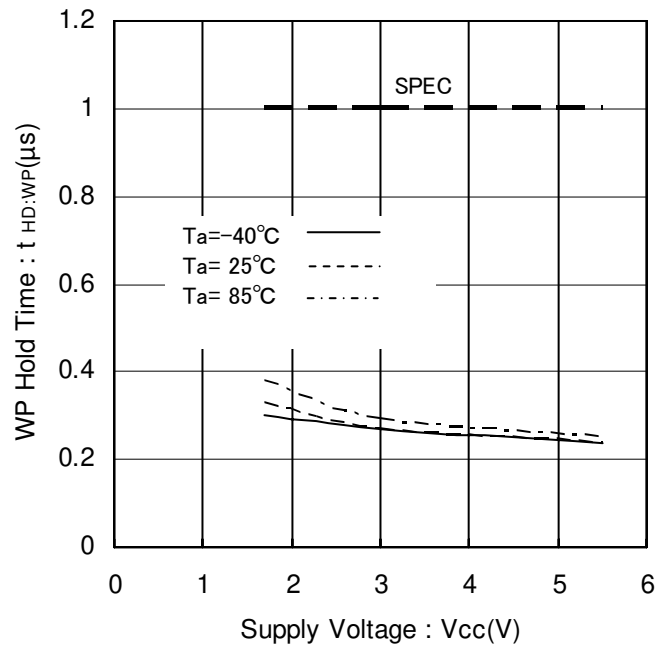


Figure 31. WP Hold Time vs Supply Voltage

Typical Performance Curves - continued

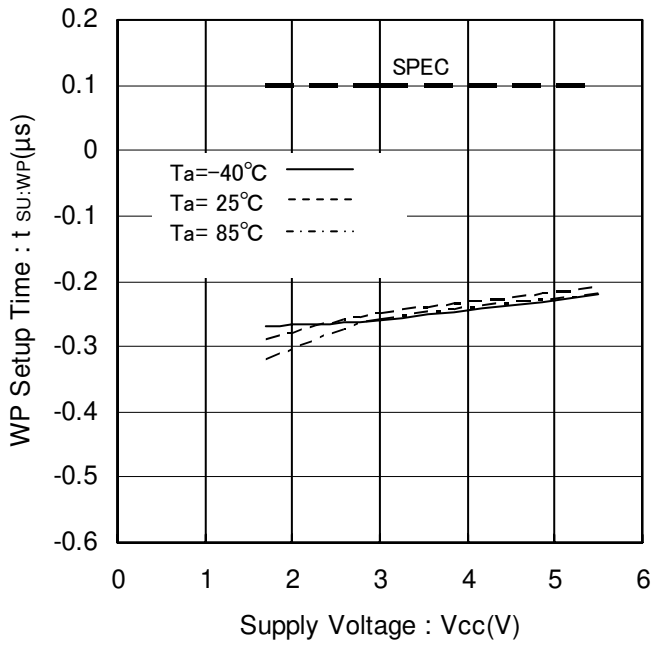


Figure 32. WP Setup Time vs Supply Voltage

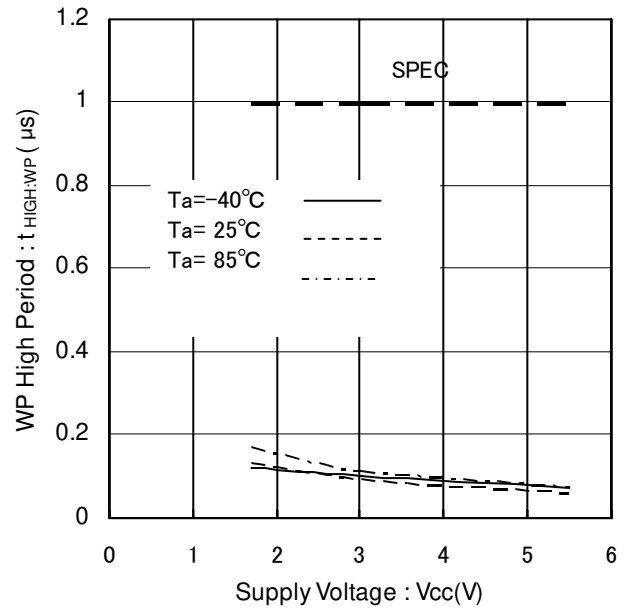


Figure 33. WP High Period vs Supply Voltage

## Timing Chart

### 1. I<sup>2</sup>C BUS Data Communication

I<sup>2</sup>C BUS data communication starts by start condition input, and ends by stop condition input. Data is always 8bit long, and acknowledge is always required after each byte. I<sup>2</sup>C BUS data communication with several devices is possible by connecting with 2 communication lines: serial data (SDA) and serial clock (SCL).

Among the devices, there should be a "master" that generates clock and control communication start and end. The rest become "slave" which are controlled by an address peculiar to each device, like this EEPROM. The device that outputs data to the bus during data communication is called "transmitter", and the device that receives data is called "receiver"..

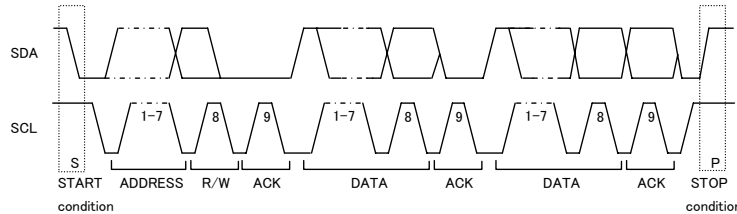


Figure 34. Data Transfer Timing

### 2. Start Condition (Start Bit Recognition)

- (1) Before executing each command, start condition (start bit) where SDA goes from 'HIGH' down to 'LOW' when SCL is 'HIGH' is necessary.
- (2) This IC always detects whether SDA and SCL are in start condition (start bit) or not, therefore, unless this condition is satisfied, any command cannot be executed.

### 3. Stop Condition (Stop Bit Recognition)

- (1) Each command can be ended by a stop condition (stop bit) where SDA goes from 'LOW' to 'HIGH' while SCL is 'HIGH'.

### 4. Acknowledge (ACK) Signal

- (1) This acknowledge (ACK) signal is a software rule to show whether data transfer has been made normally or not. In master-slave communication, the device (Ex.  $\mu$ -COM sends slave address input for write or read command to this IC) at the transmitter (sending) side releases the bus after output of 8bit data.
- (2) The device (Ex. This IC receives the slave address input for write or read command from the  $\mu$ -COM) at the receiver (receiving) side sets SDA 'LOW' during 9<sup>th</sup> clock cycle, and outputs acknowledge signal (ACK signal) showing that it has received the 8bit data.
- (3) This IC, after recognizing start condition and slave address (8bit), outputs acknowledge signal (ACK signal) 'LOW'.
- (4) After receiving 8bit data (word address and write data) during each write operation, this IC outputs acknowledge signal (ACK signal) 'LOW'.
- (5) During read operation, this IC outputs 8bit data (read data), and detects acknowledge signal (ACK signal) 'LOW'. When acknowledge signal (ACK signal) is detected, and stop condition is not sent from the master ( $\mu$ -COM) side, this IC continues to output data. When acknowledge signal (ACK signal) is not detected, this IC stops data transfer, and recognizes stop condition (stop bit), and ends read operation. Then this IC becomes ready for another transmission.

### 5. Device Addressing

- (1) Slave address comes after start condition from master.
- (2) The significant 4 bits of slave address are used for recognizing a device type. The device code of this IC is fixed to '1010'.
- (3) Next slave addresses (A2 A1 A0 --- device address) are for selecting devices, and plural ones can be used on a same bus according to the number of device addresses.
- (4) The most insignificant bit ( $R/\bar{W}$  --- READ/WRITE) of slave address is used for designating write or read action, and is as shown below.

Setting  $R/\bar{W}$  to 0 ----- write (setting 0 to word address setting of random read)

Setting  $R/\bar{W}$  to 1 ----- read

Slave address	Maximum number of Connected buses
1 0 1 0 A2 A1 A0 $R/\bar{W}$	8

**Write Command**

**1. Write Cycle**

- (1) Arbitrary data can be written to EEPROM. When writing only 1 byte, Byte Write is normally used, and when writing continuous data of 2 bytes or more, simultaneous write is possible by Page Write cycle. The maximum number of write bytes is specified per device of each capacity. Up to 64 arbitrary bytes can be written.

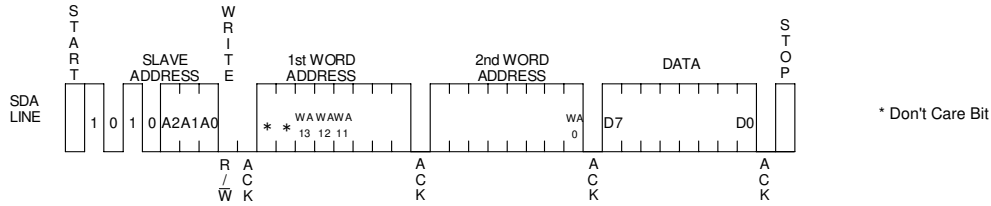


Figure 35. Byte Write Cycle

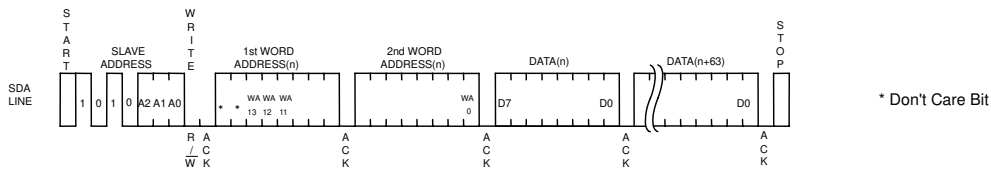


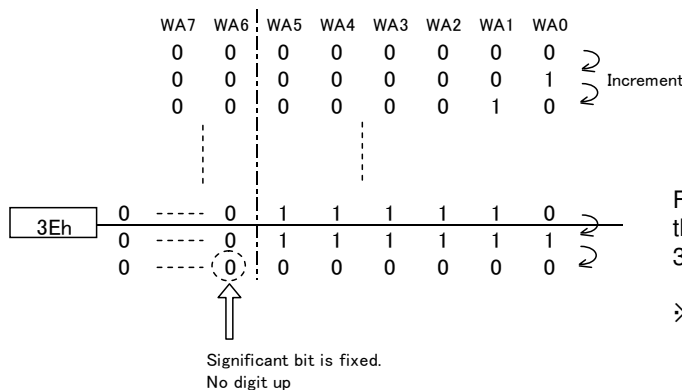
Figure 36. Page Write Cycle

- (2) During internal write execution, all input commands are ignored, therefore ACK is not returned.
- (3) Data is written to the address designated by word address (n-th address)
- (4) By issuing stop bit after 8bit data input, internal write to memory cell starts.
- (5) When internal write is started, command is not accepted for  $t_{WR}$  (5ms at maximum).
- (6) Using page write cycle, writing in bulk is done as follows: When data of more than 64 Bytes is sent, the bytes in excess overwrite the data already sent first. (Refer to "Internal Address Increment")
- (7) As for page write cycle of BR24G128-3, where 2 or more bytes of data is intended to be written, after the 8 significant bits of word address are designated arbitrarily, only the value of 6 least significant bits in the address is incremented internally, so that data up to 64 bytes of memory only can be written.

In the case BR24G128-3, 1 page=64bytes, but the page write cycle time is 5ms at maximum for 64byte bulk write. It does not stand 5ms at maximum × 64byte=320ms(Max)

**2. Internal Address Increment**

Page write mode (in the case of BR24G128-3)



For example, when it is started from address 3Eh, then, increment is made as below, 3Eh→3Fh→00h→01h... please take note.

※3Eh...3E in hexadecimal, therefore, 00111110 becomes a binary number.

**3. Write Protect (WP) Terminal**

Write Protect (WP) Function

When WP terminal is set at  $V_{CC}$  (H level), data rewrite of all addresses is prohibited. When it is set GND (L level), data rewrite of all address is enabled. Be sure to connect this terminal to  $V_{CC}$  or GND, or control it to H level or L level. Do not leave it open.

In case of using it as ROM, it is recommended to connect it to pull up or  $V_{CC}$ . At extremely low voltage at power ON/OFF, by setting the WP terminal 'H', write error can be prevented..

## Read Command

### 1. Read Cycle

Read cycle is when data of EEPROM is read. Read cycle could be random read cycle or current read cycle. Random read cycle is a command to read data by designating a specific address, and is used generally. Current read cycle is a command to read data of internal address register without designating an address, and is used when to verify just after write cycle. In both the read cycles, sequential read cycle is available where the next address data can be read in succession.

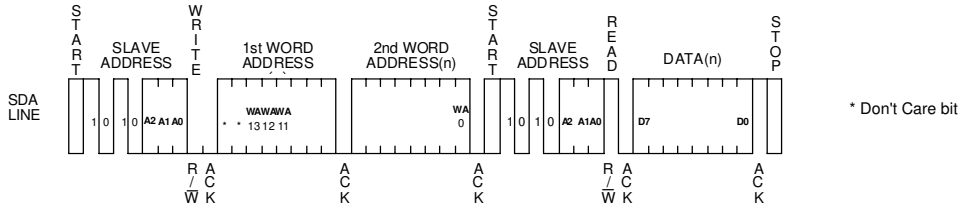


Figure 37. Random Read Cycle

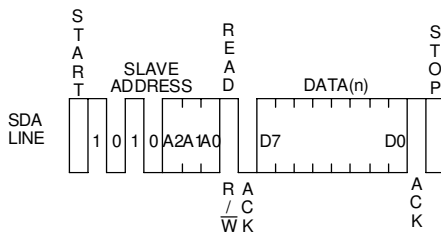


Figure 38. Current Read Cycle

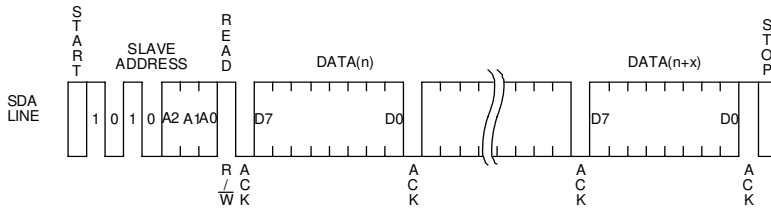


Figure 39. Sequential Read Cycle (in the case of current read cycle)

- (1) In random read cycle, data of designated word address can be read.
- (2) When the command just before current read cycle is random read cycle, current read cycle (each including sequential read cycle), data of incremented last read address (n)-th, i.e., data of the (n+1)-th address is output.
- (3) When ACK signal 'LOW' after D0 is detected, and stop condition is not sent from master ( $\mu$ -COM) side, the next address data can be read in succession.
- (4) Read cycle is ended by stop condition where 'H' is input to ACK signal after D0 and SDA signal goes from 'L' to 'H' while at SCL signal is 'H'.
- (5) When 'H' is not input to ACK signal after D0, sequential read gets in, and the next data is output. Therefore, read command cycle cannot be ended. To end read command cycle, be sure to input 'H' to ACK signal after D0, and the stop condition where SDA goes from 'L' to 'H' while SCL signal is 'H'.
- (6) Sequential read is ended by stop condition where 'H' is input to ACK signal after arbitrary D0 and SDA is asserted from 'L' to 'H' while SCL signal is 'H'.



**Software Reset**

Software reset is executed to avoid malfunction after power ON, and during command input. Software reset has several kinds, and 3 kinds of them are shown in the figure below. (Refer to Figure 40-(a), Figure 40-(b), Figure 40-(c)) Within the dummy clock input area, the SDA bus is released ('H' by pull up) and ACK output and read data '0' (both 'L' level) may be output from EEPROM. Therefore, if 'H' is input forcibly, output may conflict and over current may flow, leading to instantaneous power failure of system power source or influence upon devices.

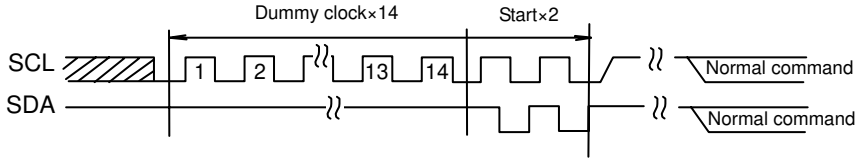


Figure 40-(a). The Case of Dummy Clock x 14 + START+START+ Command Input

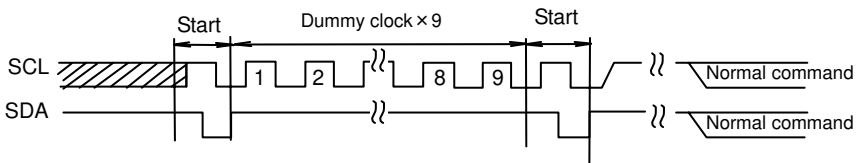


Figure 40-(b). The Case of START + Dummy Clock x 9 + START + Command Input

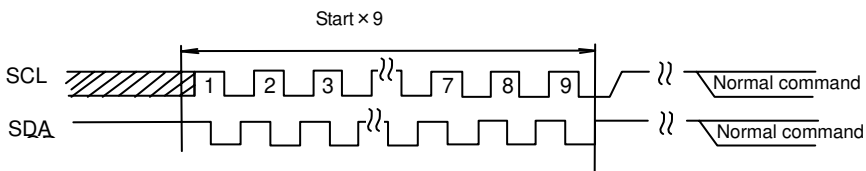


Figure 40-(c). START x 9 + Command Input

※Start command from START input.

**Acknowledge Polling**

During internal write execution, all input commands are ignored, therefore ACK is not returned. During internal automatic write execution after write cycle input, next command (slave address) is sent, and if the first ACK signal sends back 'L', then it means end of write operation, else 'H' is returned, which means writing is still in progress. By the use of acknowledge polling, next command can be executed without waiting for  $t_{WR} = 5ms$ .

To write continuously,  $R/\bar{W} = 0$ , then to carry out current read cycle after write, slave address with  $R/\bar{W} = 1$  is sent, and if ACK signal sends back 'L', then execute word address input and data output and so forth.

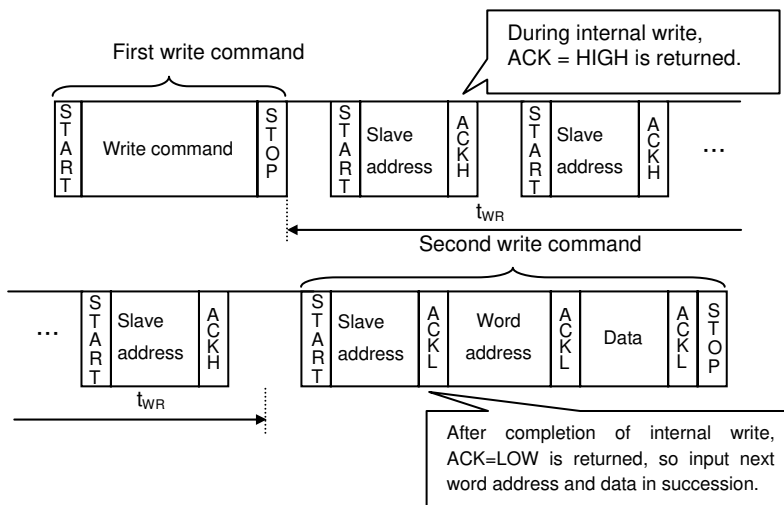


Figure 41. Case to Continuous Write by Acknowledge Polling

## WP Valid Timing (Write Cancel)

WP is usually fixed to 'H' or 'L', but when WP is used to cancel write cycle and so on, pay attention to the following WP valid timing. During write cycle execution, inside cancel valid area, by setting WP='H', write cycle can be cancelled. In both byte write cycle and page write cycle, the area from the first start condition of command to the rise of clock to take in D0 of data (in page write cycle, the first byte data) is the cancel invalid area.

WP input in this area becomes 'Don't care'. The area from the rise of SCL to take in D0 to the stop condition input is the cancel valid area. Furthermore, after the execution of forced end by WP, the IC enters standby status..

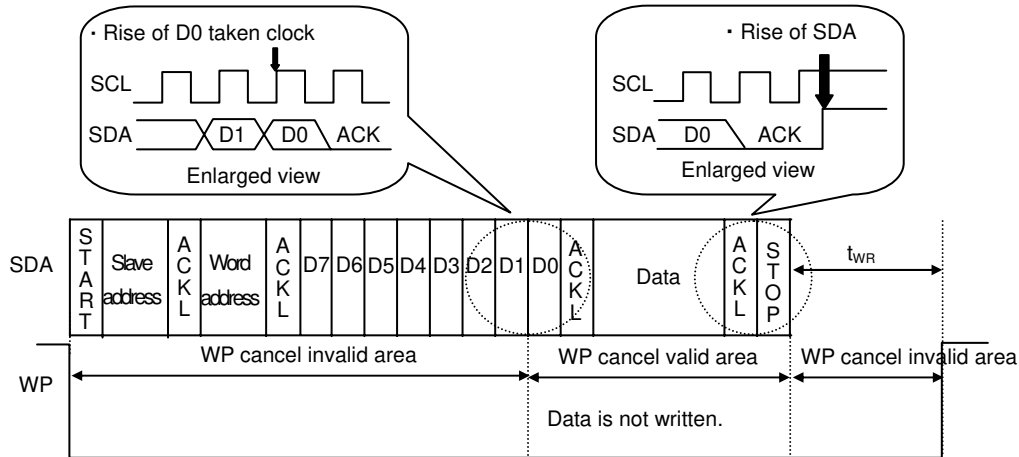


Figure 42. WP Valid Timing

## Command Cancel by Start Condition and Stop Condition

During command input, by continuously inputting start condition and stop condition, command can be cancelled. (Figure 43.) However, within ACK output area and during data read, SDA bus may output 'L'. In this case, start condition and stop condition cannot be input, so reset is not available. Therefore, execute software reset. When command is cancelled by start-stop condition during random read cycle, sequential read cycle, or current read cycle, internal setting address is not determined. Therefore, it is not possible to carry out current read cycle in succession. To carry out read cycle in succession, carry out random read cycle.

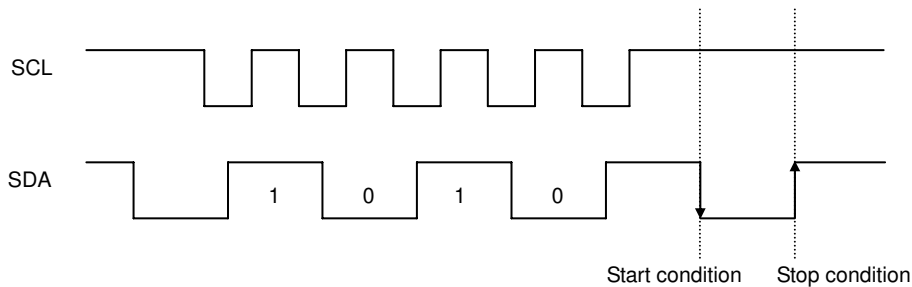


Figure 43. Case of Cancel by Start, Stop Condition during Slave Address Input

## I/O Peripheral Circuit

### 1. Pull Up Resistance of SDA Terminal

SDA is NMOS open drain, so it requires a pull up resistor. As for this resistor value ( $R_{PU}$ ), select an appropriate value from microcontroller  $V_{IL}$ ,  $I_L$ , and  $V_{OL-IOL}$  characteristics of this IC. If  $R_{PU}$  is large, operating frequency is limited. The smaller the  $R_{PU}$ , the larger is the supply current (Read).

### 2. Maximum Value of $R_{PU}$

The maximum value of  $R_{PU}$  is determined by the following factors.

(1) SDA rise time to be determined by the capacitance ( $C_{BUS}$ ) of bus line of  $R_{PU}$  and SDA should be  $t_R$  or lower.

Furthermore, AC timing should be satisfied even when SDA rise time is late.

(2) The bus electric potential (A) to be determined by input leak total ( $I_L$ ) of device connected to bus at output of 'H' to SDA bus and  $R_{PU}$  should sufficiently secure the input 'H' level ( $V_{IH}$ ) of microcontroller and EEPROM including recommended noise margin of  $0.2V_{CC}$ .

$$V_{CC} - I_L R_{PU} - 0.2 V_{CC} \geq V_{IH}$$

$$\therefore R_{PU} \leq \frac{0.8 V_{CC} - V_{IH}}{I_L}$$

Ex.)  $V_{CC} = 3V$   $I_L = 10\mu A$   $V_{IH} = 0.7 V_{CC}$   
From (2)

$$R_{PU} \leq \frac{0.8 \times 3 - 0.7 \times 3}{10 \times 10^{-6}}$$

$$\leq 30 \text{ [k}\Omega\text{]}$$

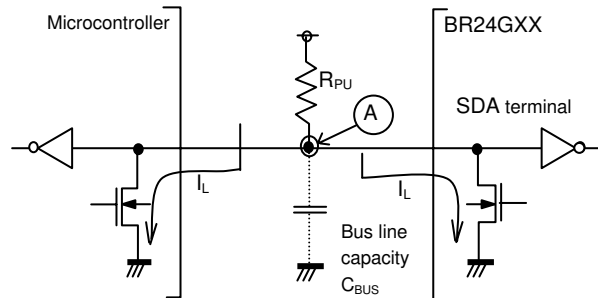


Figure 44. I/O Circuit Diagram

### 3. Minimum Value of $R_{PU}$

The minimum value of  $R_{PU}$  is determined by the following factors.

(1) When IC outputs LOW, it should be satisfied that  $V_{OLMAX} = 0.4V$  and  $I_{OLMAX} = 3mA$ .

$$\frac{V_{CC} - V_{OL}}{R_{PU}} \leq I_{OL}$$

$$\therefore R_{PU} \geq \frac{V_{CC} - V_{OL}}{I_{OL}}$$

$V_{OLMAX} = 0.4V$  should secure the input 'L' level ( $V_{IL}$ ) of microcontroller and EEPROM including recommended noise margin  $0.1V_{CC}$ .

$$V_{OLMAX} \leq V_{IL} - 0.1 V_{CC}$$

Ex.)  $V_{CC} = 3V$ ,  $V_{OL} = 0.4V$ ,  $I_{OL} = 3mA$ , microcontroller, EEPROM  $V_{IL} = 0.3V_{CC}$   
from (1)

$$R_{PU} \geq \frac{3 - 0.4}{3 \times 10^{-3}}$$

$$\geq 867 [\Omega]$$

And  $V_{OL} = 0.4 \text{ [V]}$   
 $V_{IL} = 0.3 \times 3$   
 $= 0.9 \text{ [V]}$

Therefore, the condition (2) is satisfied.

### 4. Pull-up Resistance of SCL Terminal

When SCL control is made at the CMOS output port, there is no need for a pull up resistor. But when there is a time where SCL becomes 'Hi-Z', add a pull up resistor. As for the pull up resistor value, one of several  $k\Omega$  to several ten  $k\Omega$  is recommended in consideration of drive performance of output port of microcontroller.

**Cautions on Microcontroller Connection**

**1.  $R_S$**

In I<sup>2</sup>C BUS, it is recommended that SDA port is of open drain input/output. However, when using CMOS input / output of tri state to SDA port, insert a series resistance  $R_S$  between the pull up resistor  $R_{PU}$  and the SDA terminal of EEPROM. This is to control over current that may occur when PMOS of the microcontroller and NMOS of EEPROM are turned ON simultaneously.  $R_S$  also plays the role of protecting the SDA terminal against surge. Therefore, even when SDA port is open drain input/output,  $R_S$  can be used.

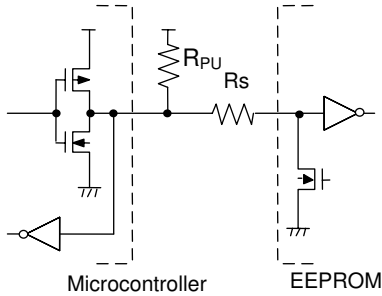


Figure 45. I/O Circuit Diagram

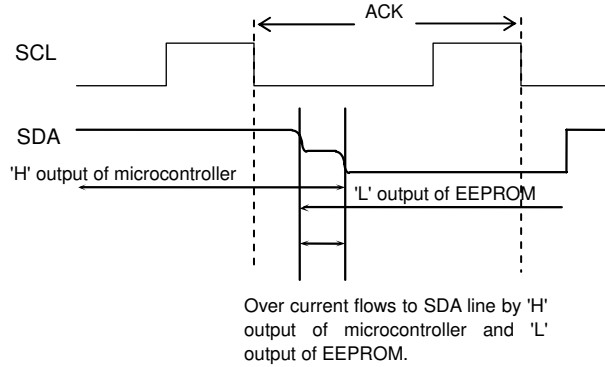


Figure 46. Input / Output Collision Timing

**2. Maximum Value of  $R_S$**

The maximum value of  $R_S$  is determined by the following relations.

- (1) SDA rise time to be determined by the capacitance ( $C_{BUS}$ ) of bus line and  $R_{PU}$  of SDA should be  $t_R$  or lower. Furthermore, AC timing should be satisfied even when SDA rise time is slow.
- (2) The bus electric potential (A) to be determined by  $R_{PU}$  and  $R_S$  the moment when EEPROM outputs 'L' to SDA bus should sufficiently secure the input 'L' level ( $V_{IL}$ ) of microcontroller including recommended noise margin of  $0.1V_{CC}$ .

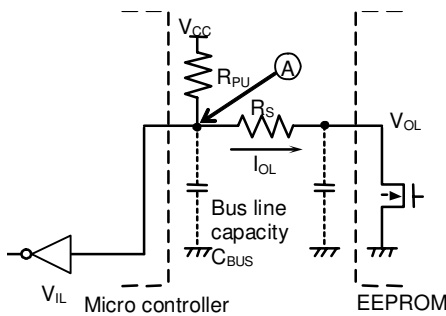


Figure 47. I/O Circuit Diagram

$$\frac{(V_{CC}-V_{OL}) \times R_S}{R_{PU}+R_S} + V_{OL} + 0.1V_{CC} \leq V_{IL}$$

$$\therefore R_S \leq \frac{V_{IL}-V_{OL}-0.1V_{CC}}{1.1V_{CC}-V_{IL}} \times R_{PU}$$

EX)  $V_{CC}=3V$   $V_{IL}=0.3V_{CC}$   $V_{OL}=0.4V$   $R_{PU}=20k\Omega$

$$R_S \leq \frac{0.3 \times 3 - 0.4 - 0.1 \times 3}{1.1 \times 3 - 0.3 \times 3} \times 20 \times 10^3$$

$$\leq 1.67 [k\Omega]$$

**3. Minimum Value of  $R_S$**

The minimum value of  $R_S$  is determined by over current at bus collision. When over current flows, noises in power source line and instantaneous power failure of power source may occur. When allowable over current is defined as  $I$ , the following relation must be satisfied. Determine the allowable current in consideration of the impedance of power source line in set and so forth. Set the over current to EEPROM at 10mA or lower.

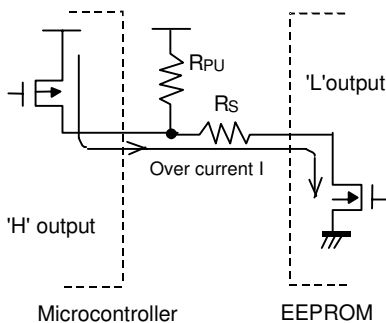


Figure 48. I/O circuit diagram

$$\frac{V_{CC}}{R_S} \leq I$$

$$\therefore R_S \geq \frac{V_{CC}}{I}$$

EX)  $V_{CC}=3V$   $I=10mA$

$$R_S \geq \frac{3}{10 \times 10^{-3}}$$

$$\geq 300 [\Omega]$$

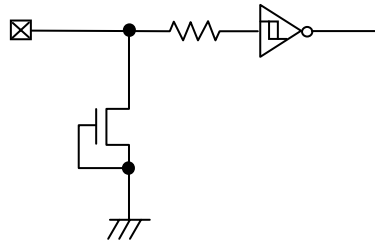
**I/O Equivalence Circuit****1. Input (A0, A1, A2, SCL, WP)**

Figure 49. Input Pin Circuit Diagram

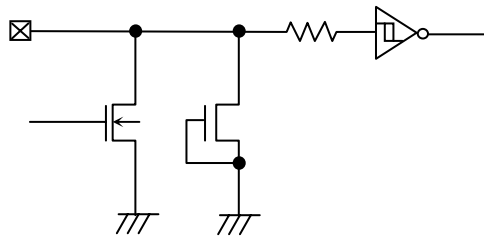
**2. Input / Output (SDA)**

Figure 50. Input / Output Pin Circuit Diagram

## Power-Up/Down Conditions

At power on, the IC's internal circuits may go through unstable low voltage area as the  $V_{CC}$  rises, making the IC's internal logic circuit not completely reset, hence, malfunction may occur. To prevent this, the IC is equipped with POR circuit and LVCC circuit. To assure the operation, observe the following conditions at power ON.

1. Set SDA = 'H' and SCL = 'L' or 'H'
2. Start power source so as to satisfy the recommended conditions of  $t_R$ ,  $t_{OFF}$ , and  $V_{bot}$  for operating POR circuit.

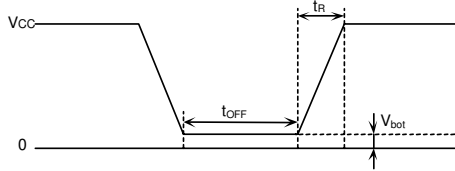


Figure 51. Rise Waveform Diagram

Recommended conditions of  $t_R$ ,  $t_{OFF}$ ,  $V_{bot}$

$t_R$	$t_{OFF}$	$V_{bot}$
10ms or below	10ms or larger	0.3V or below
100ms or below	10ms or larger	0.2V or below

3. Set SDA and SCL so as not to become 'Hi-Z'.  
When the above conditions 1 and 2 cannot be observed, take the following countermeasures.

- (1) In the case when the above condition 1 cannot be observed such that SDA becomes 'L' at power ON.  
→Control SCL and SDA as shown below, to make SCL and SDA, 'H' and 'H'.

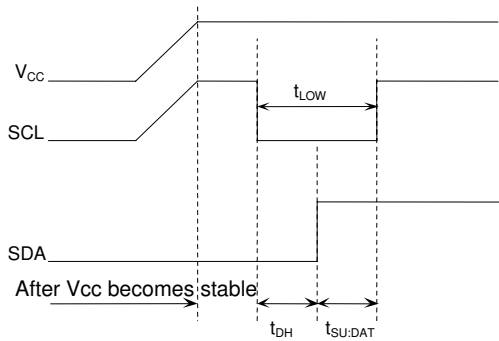


Figure 52. When SCL= 'H' and SDA= 'L'

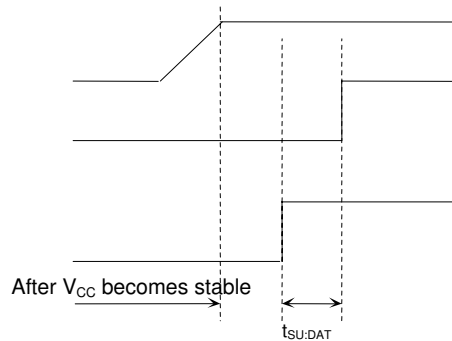


Figure 53. When SCL='L' and SDA='L'

- (2) In the case when the above condition 2 cannot be observed.  
→After power source becomes stable, execute software reset(Page16).
- (3) In the case when the above conditions 1 and 2 cannot be observed.  
→Carry out (1), and then carry out (2).

## Low Voltage Malfunction Prevention Function

LVCC circuit prevents data rewrite operation at low power, and prevents write error. At LVCC voltage (Typ =1.2V) or below, data rewrite is prevented.

## Noise Countermeasures

### 1. Bypass Capacitor

When noise or surge gets in the power source line, malfunction may occur, therefore, it is recommended to connect a bypass capacitor (0.1 $\mu$ F) between the IC's  $V_{CC}$  and GND pins. Connect the capacitor as close to IC as possible. In addition, it is also recommended to connect a bypass capacitor between board's  $V_{CC}$  and GND.

## Operational Notes

1. Described numeric values and data are design representative values only, and the values are not guaranteed.
2. We believe that the application circuit examples in this document are recommendable. However, in actual use, confirm characteristics further sufficiently. If changing the fixed number of external parts is desired, make your decision with sufficient margin in consideration of static characteristics, transient characteristics, and fluctuations of external parts and our LSI.
3. Absolute maximum ratings  
If the absolute maximum ratings such as supply voltage, operating temperature range, and so on are exceeded, LSI may be destroyed. Do not supply voltage or subject the IC to temperatures exceeding the absolute maximum ratings. In the case of fear of exceeding the absolute maximum ratings, take physical safety countermeasures such as adding fuses, and see to it that conditions exceeding the absolute maximum ratings should not be supplied to the LSI.
4. GND electric potential  
Set the voltage of GND terminal lowest at any operating condition. Make sure that each terminal voltage is not lower than that of GND terminal.
5. Thermal design  
Use a thermal design that allows for a sufficient margin by taking into account the permissible power dissipation (Pd) in actual operating conditions.
6. Short between pins and mounting errors  
Be careful when mounting the IC on printed circuit boards. The IC may be damaged if it is mounted in a wrong orientation or if pins are shorted together. Short circuit may be caused by conductive particles caught between the pins.
7. Operating the IC in the presence of strong electromagnetic field may cause malfunction, therefore, evaluate design sufficiently.

## Part Numbering

B	R	2	4	G	1	2	8	x	x	x	-	3	x	x	x	x
<b>BUS type</b> 24 : I <sup>2</sup> C																
<b>Operating temperature/ Operating Voltage</b> -40°C to +85°C / 1.6V to 5.5V																
<b>Capacity</b> 128=128K																
<b>Package</b> Blank : DIP-T8                      FJ : SOP-J8 F : SOP8                              FVT : TSSOP-B8 FV : SSOP-B8                      FVM : MSOP8 FVJ : TSSOP-B8J NUX : VSON008X2030																
<b>Process Code</b> <b>G</b> : Halogen free <b>Blank</b> : Not Halogen free As an exception, VSON008X2030 package will be Halogen free with "Blank" <b>T</b> : 100% Sn <b>Blank</b> : 100% Sn																
<b>Packaging and Forming Specification</b> E2 : Embossed tape and reel (SOP8,SOP-J8, SSOP-B8,TSSOP-B8, TSSOP-B8J) TR : Embossed tape and reel (MSOP8, VSON008X2030) None : Tube (DIP-T8)																

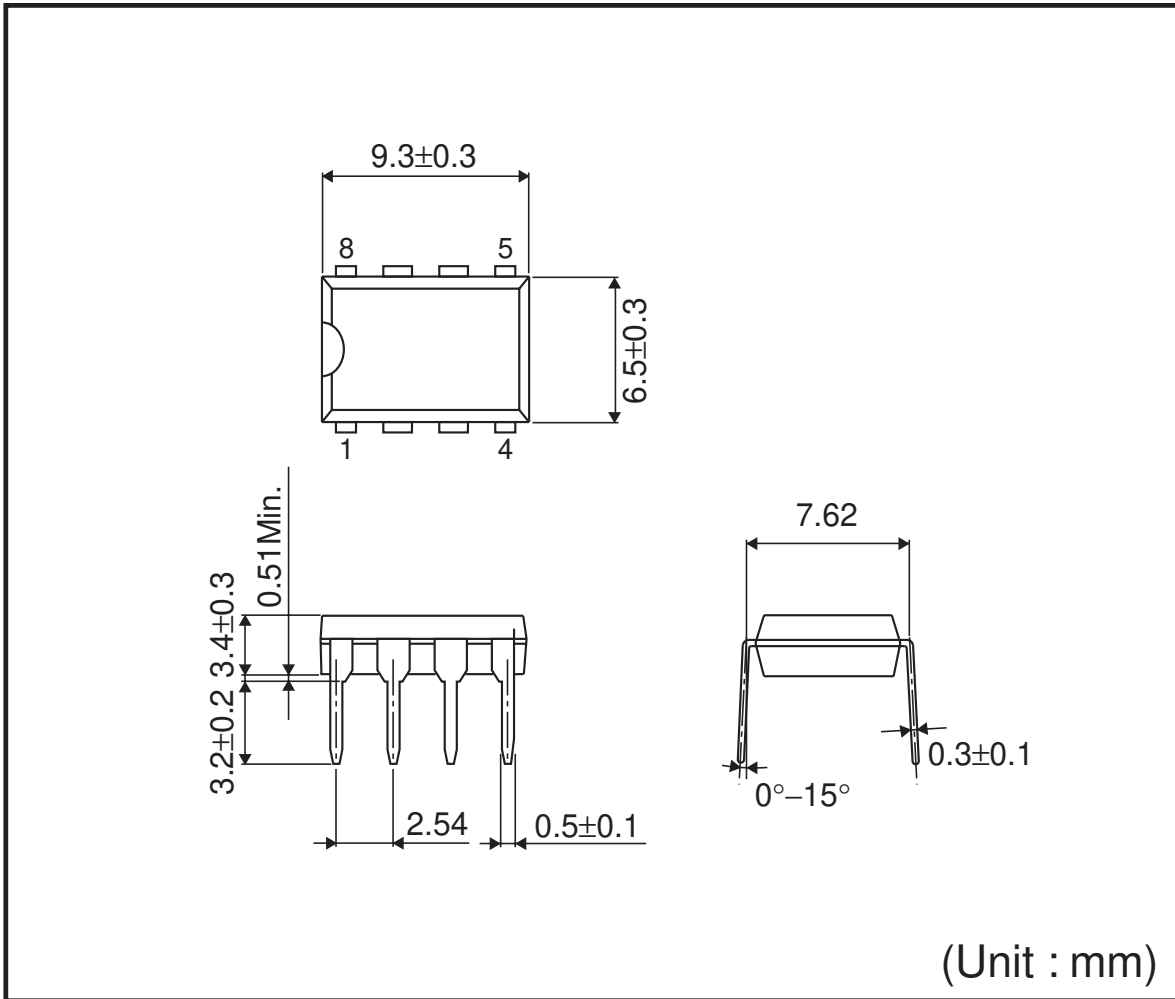
## Lineup

Capacity	Package		Orderable Part Number	Remark	
	Type	Quantity			
128K	DIP-T8	Tube of 2000	BR24G128 -3	Not Halogen free	100% Sn
	SOP8	Reel of 2500	BR24G128F -3GTE2	Halogen free	100% Sn
	SOP-J8		BR24G128FJ -3GTE2	Halogen free	100% Sn
	SSOP-B8	Reel of 2500	BR24G128FV -3GTE2	Halogen free	100% Sn
	TSSOP-B8	Reel of 3000	BR24G128FVT -3GE2	Halogen free	100% Sn
	TSSOP-B8J	Reel of 2500	BR24G128FVJ -3GTE2	Halogen free	100% Sn
	MSOP8	Reel of 3000	BR24G128FVM -3GTTR	Halogen free	100% Sn
	VSON008X2030	Reel of 4000	BR24G128NUX -3TTR	Halogen free	100% Sn



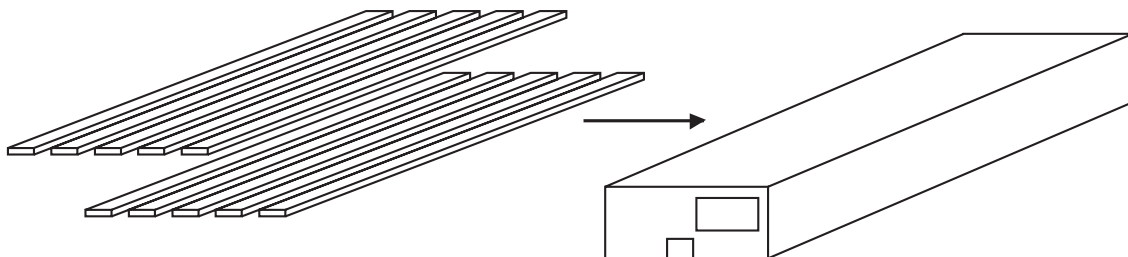
Physical Dimensions Tape and Reel Information

# DIP-T8



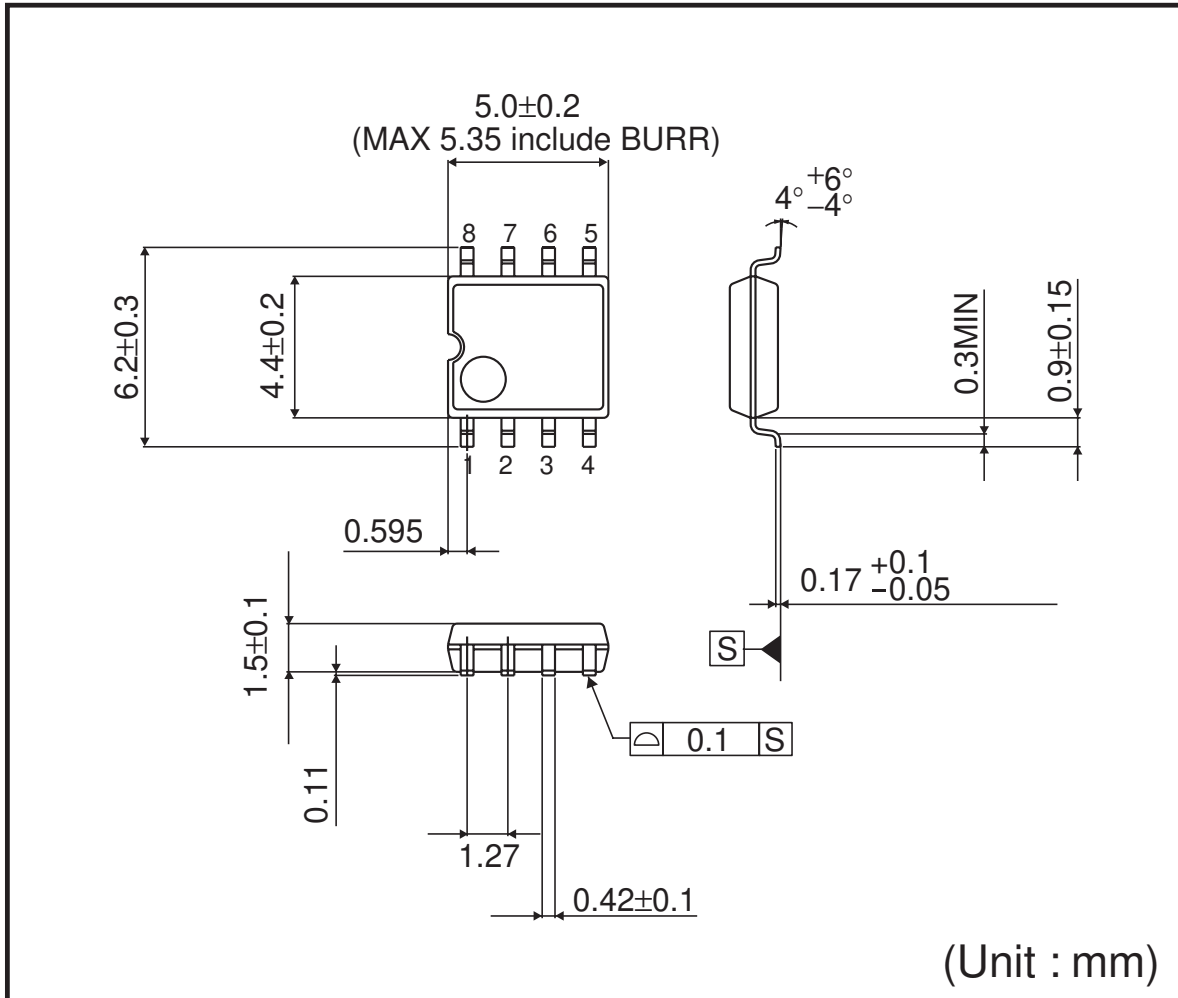
<Tape and Reel information>

Container	Tube
Quantity	2000pcs
Direction of feed	Direction of products is fixed in a container tube



\*Order quantity needs to be multiple of the minimum quantity.

# SOP8



### <Tape and Reel information>

Tape	Embossed carrier tape
Quantity	2500pcs
Direction of feed	E2 ( The direction is the 1pin of product is at the upper left when you hold reel on the left hand and you pull out the tape on the right hand )

